

PCN # 1357

DATE: October 30, 2013

**Quality Assurance** 160 Rio Robles San Jose, CA 95134

## X PROCESS CHANGE NOTICE PRODUCT CHANGE NOTICE

			OTIFICATION OF C FOLLOWING CATE		
DESIGN	WAFER FAB	ASSEMBL			
		AFFECTED	PRODUCT:		
	Ordering P/		sting XLS in PCN ZIP	file)	
CHANGE FROM: C	urrent Test Facility at Maxim I	Dallas, Texas	CHANGE TO: Addi	ing additional Test Facility at KYEC, Tai	iwan
JUSTIFICATION: Fo	or supply continuity by adding	additional test	facility. KYEC is a N	Maxim qualified test site for other produc	ets.
TRACEABILITY: M	IAXIM maintains traceable by	markings as b	randed on packaged u	nits.	
Maxim's Change Not improvements.	ification System is designed to	keep our cus		I of major product, manufacturing, or fa	ncility
				Deborah Meeker / PCN Coordinator	
For further information	on, please contact either of the	people listed b	elow.		
Contact your local M	Maxim Company Representa	tive or	Deborah Meeker, I 408-601-5618 / pci	PCN Coordinator n.coordinator@maxim-ic.com	
Document Title: Product Change Notice - Notification Only				Document ID: 18-05	582/J